

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/706,397	BETARBET, SANDEEP	
Examiner		Art Unit		Page 1 of 1
Greg Bengzon		2144		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,065,547 B2	06-2006	Persels et al.	709/200
*	B	US-2004/0153451 A1	08-2004	Phillips et al.	707/008
*	C	US-2004/0199514 A1	10-2004	Rosenblatt et al.	707/010
*	D	US-2004/0203636 A1	10-2004	Chan et al.	455/414.1
*	E	US-2004/0088348 A1	05-2004	Yeager et al.	709/202
*	F	US-5,944,783 A	08-1999	Nieten, Joseph Lee	709/202
*	G	US-7,254,608 B2	08-2007	Yeager et al.	709/203
*	H	US-2002/0147774 A1	10-2002	Lisiecki et al.	709/203
*	I	US-2004/0039781 A1	02-2004	LaVallee et al.	709/205
*	J	US-2002/0143888 A1	10-2002	Lisiecki et al.	709/214
*	K	US-2003/0014530 A1	01-2003	Bodin et al.	709/231
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.